Search Notes

Application/Control No	Applicant(s)/Patent und Reexamination	er
10/722,609	NAKAJIMA, AKIRA	
Examiner	Art Unit	
Tuan Quach	2826	

SEARCHED					
Class	Subclass	Date	Examiner		
257	88, 443, 444, 686, 777, 782	3/18/2005	ΤQ		
257	783	3/18/2005	TQ		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST (USPAT; USPGPUB; DERWENT; EPO; JPO; IBMTDB)	3/18/2005	TQ